Tuesday, April 16, 2019

WHITE PAPERS
& APPLICATION NOTES

DOWNLOAD FREE WHITE PAPERS & APPLICATION NOTES


ANASYS INSTRUMENTS
The world leader in nanoscale IR spectroscopy
BRUKER

Application Note #201
High-Resolution Chemical Imaging with Tapping AFM-IR

High-Resolution Chemical Imaging with Tapping AFM-IR

Where the spatial resolution of conventional bulk IR spectroscopy is limited by diffraction to ~3-10 µm, atomic force microscopy (AFM) provides a nanoscale topographic map of a sample surface. However, AFM has been unable traditionally to chemically characterize materials. This article discusses Tapping AFM-IR, which is a photothermal technique that combines AFM and IR spectroscopy to unambiguously identify the chemical composition of a sample with tens-of-nanometers spatial resolution.

DOWNLOAD NOW

Sponsored by

BRUKER

PHOTONICS MEDIA

Visit Photonics Media to download other white papers and learn more about the latest developments in lasers, imaging, optics, biophotonics, machine vision, spectroscopy, microscopy, photovoltaics and more.

www.photonics.com/WhitePapers.aspx